



SIGC20T120L

IGBT³ Chip

FEATURES:

- 1200V Trench + Field Stop technology
- 120µm chip
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

power module



Applications:

• drives

Chip Type	V _{CE}	I _{Cn}	Die Size	Package	Ordering Code
SIGC20T120L	1200V	15A	4.41 x 4.47 mm ²	sawn on foil	Q67050- A4205-A101

MECHANICAL PARAMETER:

Raster size	4.41 x 4.47				
Emitter pad size	2.99 x 2.9				
Gate pad size	1.1 x 0.7				
Area total / active	19.7 / 12.8				
Thickness	120	μm			
Wafer size	150	mm			
Flat position	0	grd			
Max.possible chips per wafer	748 pcs				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, <500μm				
Reject Ink Dot Size	Ø 0.65mm; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



SIGC20T120L

MAXIMUM RATINGS:

Parameter	Symbol	Value	Unit
Collector-emitter voltage	V _{CE}	1200	V
DC collector current, limited by T _{jmax}	I _C	15	А
Pulsed collector current, t _p limited by T _{jmax}	I _{cpuls}	30	А
Gate emitter voltage	V _{GE}	±20	V
Operating junction and storage temperature	T_j , T_{stg}	-55 + 150	°C

STATIC CHARACTERISTICS (tested on chip), T_j =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
i drametei		Conditions	min.	typ.	max.	J
Collector-emitter breakdown voltage	V _{(BR)CES}	V_{GE} =0V , I_{C} = 0.5mA	1200			
Collector-emitter saturation voltage	V _{CE(sat)}	V _{GE} =15V, I _C =15A	1.35	1.65	2.05	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	I_C =600 μ A , V_{GE} = V_{CE}	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			100	μΑ
Gate-emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =30V			120	nA
Integrated gate resistor	R _{Gint}					Ω

ELECTRICAL CHARACTERISTICS (tested at component):

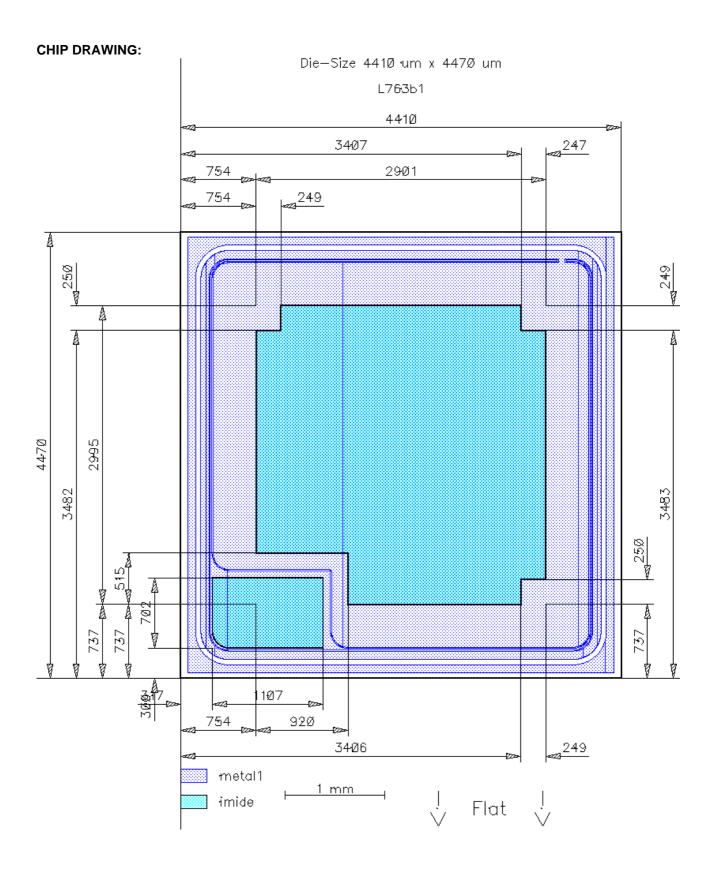
Parameter	Symbol	Conditions	Value			Unit
rarameter	Syllibol	Conditions	min.	typ.	max.	Onic
Input capacitance	Ciss	$V_{CE}=25V$,		1090		pF
Output capacitance	Coss	$V_{GE}=0V$,		58		
Reverse transfer capacitance	Crss	f=1MHz		48		

SWITCHING CHARACTERISTICS (tested at component), Inductive Load

Parameter	Symbol	Conditions	Value			Unit
raidilletei			min.	typ.	max.	Ullit
Turn-on delay time	$t_{d(on)}$	<i>T</i> _j =125°C		tbd		ns
Rise time	$t_{\rm r}$	$V_{CC} = 600 \text{ V},$		tbd		
Turn-off delay time	$t_{d(off)}$	I _C =15A, V _{GE} =-15/15V,		tbd		
Fall time	t _f	$R_{\rm G}$ = 75 Ω		tbd		



SIGC20T120L





Preliminary

SIGC20T120L

This chip data sheet refers to the device data sheet

DESCRIPTION:

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

Published by Infineon Technologies AG i Gr., Bereich Kommunikation St.-Martin-Strasse 53, D-81541 München © Infineon Technologies AG 1999 All Rights Reserved.

Attention please!

The information herein is given to describe certain components and shall not be considered as warranted characteristics.

Terms of delivery and rights to technical change reserved.

We hereby disclaim any and all warranties, including but not limited to warranties of non-infringement, regarding circuits, descriptions and charts stated herein.

Infineon Technologies is an approved CECC manufacturer.

Information

For further information on technology, delivery terms and conditions and prices please contact your nearest Infineon Technologies Office in Germany or our Infineon Technologies Representatives world-wide (see address list).

Warnings

Due to technical requirements components may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies Office.

Infineon Technologies components may only be used in life-support devices or systems with the express written approval of Infineon Technologies, if a failure of such components can reasonably be expected to cause the failure of that life-support device or system, or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body, or to support and / or maintain and sustain and / or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.